

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination TANAKA ET AL.	
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**U.S. PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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**FOREIGN PATENT DOCUMENTS**

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X O	JP 62018056 A	01-1987	Japan	ITAHANA et al.	
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